The goal of NanoBonding<sup>TM</sup> is to form molecular cross-bridges at the interface.



Figure 1: Details NanoBonding<sup>TM</sup> process

This is accomplished by creating a hydrophilic GaAs surface and a hydrophobic Silicon surface.





The figure above displays the effect of etching on the surface energies of  $y^{T}$ ,  $y^{LW}$ ,  $y^{+}$  and,  $y^{-}$  Si(100) surfaces. As received Boron-doped p- Si(100) wafers are hydrophilic before etching and made hydrophobic when etched with the Herbots-Atluri (HA) process as evidenced by the decrease in  $y^{T}$  and the increase in  $y^{LW}$ . After etching,  $y^{LW}$  is 98% of  $y^{T}$ , implicating that etching makes the surface less interactive and more hydrophobic.



Figure 3: 3LCAA surface energy measurements for GaAs(100)

Figure3 above displays the effect of etching on GaAs(100) surfaces. As received Te n+ doped GaAs(100) wafers are hydrophobic before etching and are made more hydrophilic by a proprietary passivation based etch as evidenced by the increase in  $y^{T}$  and the decrease in  $y^{LW}$ . After etching,  $y^{LW}$  is only 66% of  $y^{T}$ , implying that etching makes the surface more interactive and more hydrophilic.



Figure 4: IBA Spectra for Si(100) and GaAs(100) with channeling along <111> crystal axis. Fig 4(a) (b), (c) and (d) display each three IBA spectra at the oxygen maximum resonance energy of  $3.049 \pm 0.010$  MeV, obtained by overlaying three spectra at the same energy on the same sample as follows: a Rotating Random geometries , a SIMNRA simulation, and <111> axial Channeling. The SIMNRA simulations and RR data match within 1% the oxygen counts, which are identical in RR and <111> channeling. Aqueous HF etch if found to reduce the amount of oxygen on the Si(100) surface by 11.6% . A proprietary etch reduces the amount of oxygen on GaAs(100) by 49.1% and stabilize that amount for days.